

# RF Low Noise FET CE3514M4

# 12GHz Low Noise FET in Dual Mold Plastic PKG

### **DESCRIPTION**

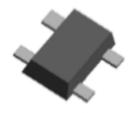
- Low Noise and High Gain
- Original Dual Mold Plastic package

### **FEATURES**

 Low noise figure and high associated gain NF=0.42dB TYP., Ga=12.2dB TYP. @VDS=2V, ID=10mA, f=12GHz

### **PACKAGE**

 Flat-lead 4-pin thin-type super minimold package



### **APPLICATIONS**

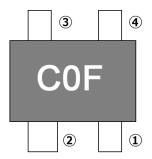
- DBS LNB gain-stage, Mix-stage
- Low noise amplifier for microwave communication systems

### ORDERING INFORMATION

Part Number	Order Number	Package	Marking	Description
CE3514M4	CE3514M4-C2	Flat-lead 4-pin thin-type super minimold package	COF	<ul> <li>Embossed tape 8 mm wide</li> <li>Pin 1(Source), Pin 2 (Drain)</li> <li>Face the perforation side of the Tape</li> <li>MOQ 15 kpcs/reel</li> </ul>



# **PIN CONFIGURATION:**



PIN No.	PIN Name
1	Source
2	Drain
3	Source
4	Gate

# **ABSOLUTE MAXIMUM RATINGS**

(TA = +25°C, unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain to Source Voltage	$V_{DS}$	4.0	V
Gate to Source Voltage	V <sub>GS</sub>	-3.0	V
Drain Current	I <sub>D</sub>	I <sub>DSS</sub>	mA
Gate Current	I <sub>G</sub>	80	μA
Total Power Dissipation	P <sub>tot</sub>	125	mW
Channel Temperature	T <sub>ch</sub>	+150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +125	°C
Operation Temperature	T <sub>op</sub>	-55 to +125 <sup>Note</sup>	°C

Note Refer to Total Power Dissipation vs. Ambient Temperature graph on page 4

# RECOMMENDED OPERATING RANGE

(TA = +25°C, unless otherwise specified)

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Drain to Source Voltage	$V_{DS}$	+1	+2	+3	V
Drain Current	I <sub>D</sub>	5	10	15	mA



# **ELECTRICAL CHARACTERISTICS**

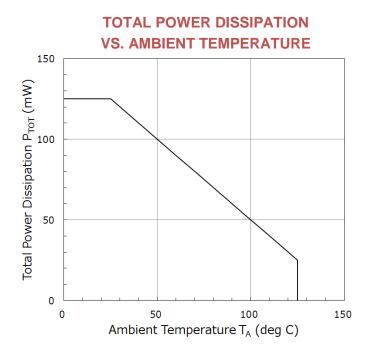
(TA = +25°C, unless otherwise specified)

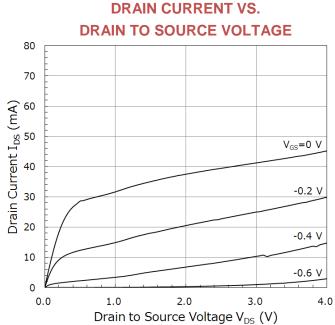
Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Gate to Source Leak Current	I <sub>GSO</sub>	V <sub>GS</sub> = -3.0V	-	0.4	10	μΑ
Saturated Drain Current	I <sub>DSS</sub>	$V_{DS} = 2V$ , $V_{GS} = 0V$	27	47.5	68	mA
Gate to Source Cut-off Voltage	$V_{GS(off)}$	$V_{DS} = 2V, I_D = 120\mu A$	-1.10	-0.75	-0.39	V
Transconductance	Gm	$V_{DS} = 2V$ , $I_D = 10mA$	54	69	-	mS
Noise Figure	NF	$V_{DS} = 2V, I_{D} = 10mA,$	-	0.42	0.62	dB
Associated Gain	Ga	f = 12GHz	10.5	12.2	-	dB

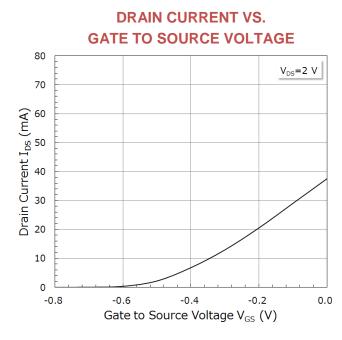


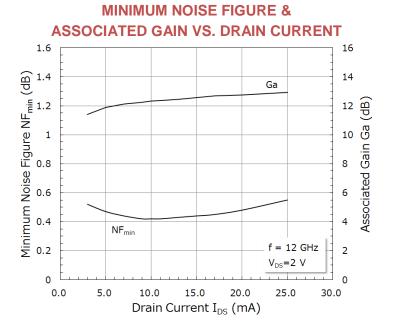
## **TYPICAL CHARACTERISTICS:**

(TA=+25℃, unless otherwise specified)











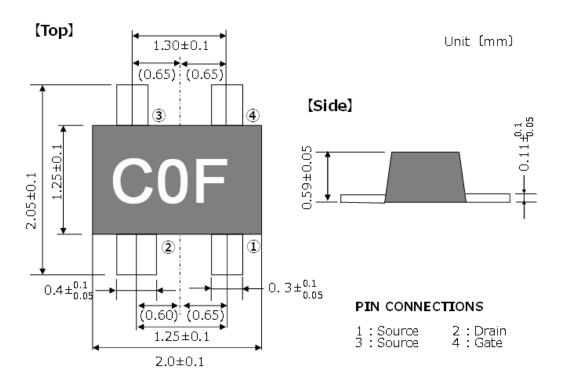
# **S-PARAMETERS**

S-Parameters are available on the CEL web site.

# RECOMMENDED SOLDERING CONDITIONS

Recommended Soldering Conditions are provided on the CEL web site.

# **PACKAGE DIMENSIONS**





# **REVISION HISTORY**

Version	Change to current version	Page(s)
CDS-0021-02 (Issue A)	Initial datasheet	N/A
July 28, 2016		



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### [CAUTION]

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- Do not dispose in fire or break up this product.
- Do not chemically make gas or powder with this product.
- When discarding this product, please obey the laws of your country.
- Do not lick the product or in any way allow it to enter the mouth.

### [CAUTION]

Although this device is designed to be as robust as possible, ESD (Electrostatic Discharge) can damage this device. This device must be protected at all times from ESD. Static charges may easily produce potentials of several kilovolts on the human body or equipment, which can discharge without detection. Industry-standard ESD precautions should be used at all times.

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